SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995

- Compare Two 8-Bit Words
- Choice of Totem-Pole or Open-Collector Outputs
- SN74ALS518 and 'ALS520 Have 20-kΩ Pullup Resistors on Q Inputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

ТҮРЕ	INPUT PULLUP RESISTOR	OUTPUT FUNCTION AND CONFIGURATION
SN74ALS518	Yes	P = Q open collector
'ALS520	Yes	P = Q totem pole
SN74ALS521‡	No	P = Q totem pole

\$ SN74ALS521 is identical to 'ALS688.

description

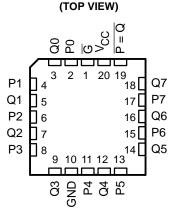
These identity comparators perform comparisons on two 8-bit binary or BCD words. The SN74ALS518 provides P = Q outputs, while the 'ALS520 and SN74ALS521 provide $\overline{P} = \overline{Q}$ outputs. The SN74ALS518 has an open-collector output. The SN74ALS518 and 'ALS520 feature 20-k Ω pullup resistors on the Q inputs for analog or switch data.

The SN54ALS520 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74ALS518, SN74ALS520, and SN74ALS521 are characterized for operation from 0°C to 70°C.

SN54ALS520 J PACKAGE SN74ALS518, SN74ALS520, SN74ALS521 DW OR N PACKAGE (TOP VIEW)									
G P 0 Q 0 P 1 Q 1 Q 1 Q 2 Q 2 Q 2 Q 2 G S D	1 2 3 4 5 6 7 8 9 10	20 V_{CC} 19 $P = Q/P = Q^{\dagger}$ 18 Q^{7} 17 P^{7} 16 Q^{6} 15 P^{6} 14 Q^{5} 13 P^{5} 12 Q^{4} 11 P^{4}							
9.15 4	10								

 $\frac{P = Q}{P = Q}$ for SN74ALS518 P = Q for 'ALS520 and SN74ALS521

SN54ALS520 ... FK PACKAGE



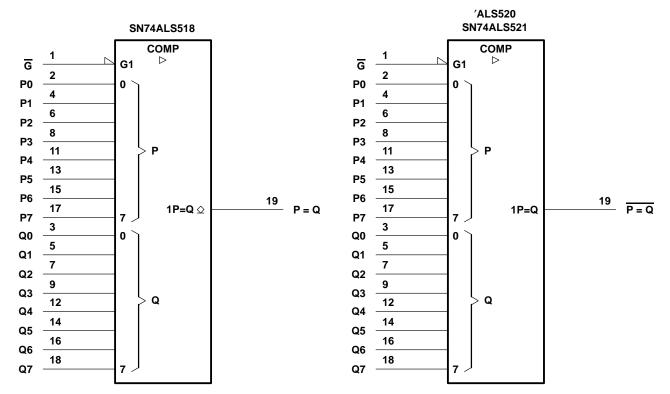
FUNCTION TABLE

IN	PUTS	OUT	PUTS
DATA P, Q	ENABLE G	-E P=Q P=	
P = Q	L	Н	L
P > Q	L	L	Н
P < Q	L	L	Н
Х	Н	L	Н

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995

logic symbols[†]

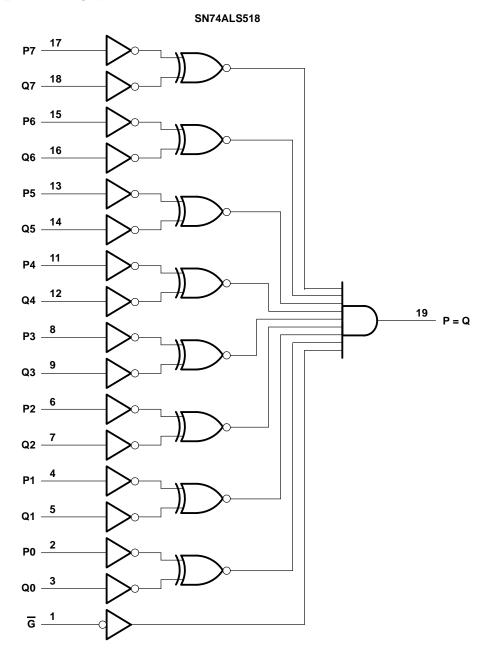


[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995

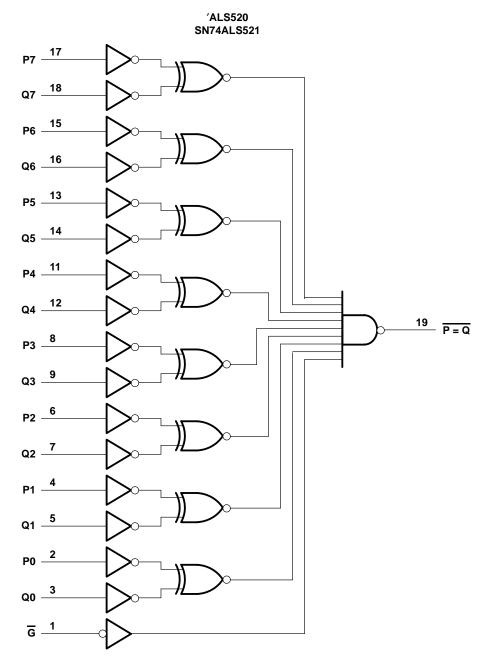
logic diagrams (positive logic)





SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995

logic diagrams (positive logic) (continued)





SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC}	
Input voltage, V _I : Q inputs All other inputs	
Off-state output voltage	
Operating free-air temperature range, T _A : SN74ALS518	
Storage temperature range	−65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN74ALS518			UNIT
		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
VOH	High-level output voltage			5.5	V
IOL	Low-level output current			24	mA
TA	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			SN74ALS518		
		TESTCO	TEST CONDITIONS			MAX	UNIT
VIK		V _{CC} = 4.5 V,	lj = -18 mA			-1.5	V
IOH		V _{CC} = 5.5 V,	V _{OH} = 5.5 V			0.1	mA
		V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4	v
VOL		VCC = 4.5 V	I _{OL} = 24 mA		0.35	0.5	v
1.	Q inputs		V _I = 5.5 V			0.1 m/	mA
11	All other inputs	v _{CC} = 5.5 v	V ₁ = 7 V			0.1	mA
Lu .	Q inputs	$V_{CC} = 5.5 V$ $V_{I} = 7 V$ $V_{CC} = 5.5 V$, $V_{I} = 27 Y v$		-0.2	mA		
ΙΗ	All other inputs	vcc = 5.5 v,	v = 2.7 v			20	μA
	Q inputs					-0.6	A
ΙIL	All other inputs	V _{CC} = 5.5 V,	V∣ =℃!¥′ ∨			-0.1	mA
ICC		V _{CC} = 5.5 V,	See Note 1		11	17	mA

[‡] All typical values are at $V_{CC} = 5$ V, $T_A = 25^{\circ}$ C.

NOTE 1: I_{CC} is measured with G grounded, and P and Q at 4.5 V.



SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$\label{eq:CC} \begin{array}{c} V_{CC} = 4.5 \ V \ to \ 5.5 \ V, \\ C_L = 50 \ pF, \\ R_L = 680 \ \Omega, \\ T_A = MIN \ to \ MAX^{\dagger} \\ \hline \\ SN74ALS518 \end{array}$		UNIT
			MIN	MAX	
^t PLH	D an O		15	33	
^t PHL	P or Q	P = Q	3	15	ns
^t PLH	G	P = Q	15	33	
^t PHL	6	F = Q	3	15	ns

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC}
Input voltage, VI: Q inputs of 'ALS520 V _{CC} + 0.5 V or 5.5 V, whichever is less
All other inputs
Operating free-air temperature range, T _A : SN54ALS520 –55°C to 125°C
SN74ALS520, SN74ALS521 0°C to 70°C
Storage temperature range

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN	54ALS5	20	SN74ALS520 SN74ALS521		UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-1			-2.6	mA
IOL	Low-level output current			12			24	mA
TA	Operating free-air temperature	-55		125	0		70	°C



SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995

PARAMETER		TEST CONDITIONS		SN	SN54ALS520			SN74ALS520 SN74ALS521			
				MIN	түр†	MAX	MIN	түр†	MAX		
VIK		V _{CC} = 4.5 V,	lj = - 18 mA			-1.5			-1.5	V	
		V_{CC} = 4.5 V to 5.5 V,	I _{OH} = - 0.4 mA	V _{CC} -2	2		V _{CC} -2				
VOH			I _{OH} = – 1 mA	2.4	3.3					V	
		V _{CC} = 4.5 V	I _{OH} = - 2.6 mA				2.4	3.2			
Vei			I _{OL} = 12 mA		0.25	0.4		0.25	0.4		
VOL		$V_{CC} = 4.5 V$	I _{OL} = 24 mA					0.35	0.5		
1.	'ALS520 Q inputs	V _{CC} = 5.5 V	V _I = 5.5 V			0.1			0.1	A	
lj –	All other inputs		V _I = 7 V			0.1			0.1	mA	
	'ALS520 Q inputs					-0.2			-0.2	mA	
ΙΗ	All other inputs	V _{CC} = 5.5 V,	$= 5.5 \text{ V}, \qquad \text{V}_{\text{I}} = 27.9^{\circ} \text{ v}$			20			20	μA	
	'ALS520 Q inputs					-0.6			-0.6	A	
۱	All other inputs	V _{CC} = 5.5 V,	= 5.5 V, V _I = °C!¥ v			-0.1			-0.1	mA	
10 [‡]		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA	
	'ALS520		Coo Note 4		12	19		12	19	A	
ICC	SN74ALS521	V _{CC} = 5.5 V,	See Note 1		12	19		12	19	mA	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$. [‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS. NOTE 1: I_{CC} is measured with \overline{G} grounded, and P and Q at 4.5 V.

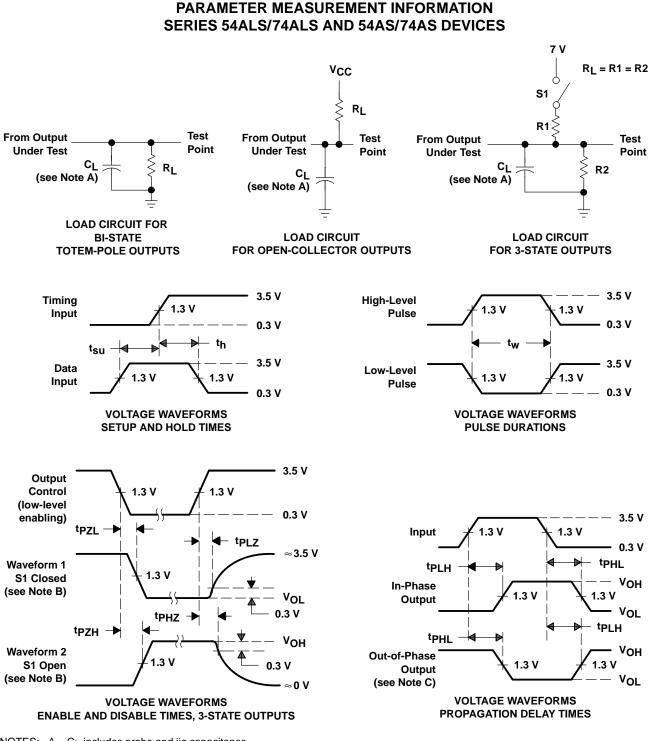
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	то	VC CL RL TA	UNIT			
		(OUTPUT)	SN54ALS520		SN74ALS520 SN74ALS521		
			MIN	MAX	MIN	MAX	
^t PLH	Dero	$\overline{P} = Q$	3	19	3	12	
^t PHL	P or Q	P=Q	3	25	5	20	ns
^t PLH	G	<u>P = Q</u>	2	18	2	12	
^t PHL	9	F=Q	5	23	5	22	ns

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



SDAS224B - JUNE 1982 - REVISED NOVEMBER 1995



NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: $PRR \le 1$ MHz, $t_f = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated